

2SJ76-VB Datasheet P-Channel 100 V (D-S) 175 °C MOSFET

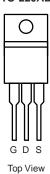
PRODUCT SUMMARY				
V _{DS} (V)	- 100			
$R_{DS(on)}(\Omega)$ at $V_{GS} = -10 \text{ V}$	0.033			
$R_{DS(on)}(\Omega)$ at $V_{GS} = -4.5 \text{ V}$	0.037			
I _D (A)	- 50			
Configuration	Single			

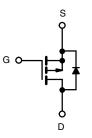
FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Trench Power MOSFET
- Package with Low Thermal Resistance
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2002/95/EC









P-Channel	MOSFET
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ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V_{DS}	- 100	V	
Gate-Source Voltage		V_{GS}	± 20	V	
Continuous Drain Current	T _C = 25 °C	L	- 50		
	T _C = 125 °C	- I _D	- 30		
Continuous Source Current (Diode Conduction)a		I _S	- 50	Α	
Pulsed Drain Current ^b		I _{DM}	- 180		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	- 44		
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	96	mJ	
Maximum Power Dissipation ^b	T _C = 25 °C	P ₅	136	W	
	T _C = 125 °C		45	۷V	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C	

THERMAL RESISTANCE RATINGS					
PARAMETER		SYMBOL	LIMIT	UNIT	
Junction-to-Ambient	PCB Mount ^c	R_{thJA}	50	°C/W	
Junction-to-Case (Drain)		R _{thJC}	1.1	C/VV	

Notes

- a. Package limited.
- b. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.
- c. When mounted on 1" square PCB (FR-4 material).
- d. Parametric verification ongoing.



SPECIFICATIONS (T _C = 25 °C, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static	1				ı	ı	_
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		- 100 - 1.0	-	-	V
Gate-Source Threshold Voltage	V _{GS(th)}		$V_{DS} = V_{GS}, I_{D} = -250 \mu A$		-	-2.5	
Gate-Source Leakage	I _{GSS}		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$		-	± 100	nA
		$V_{GS} = 0 V$	V _{DS} = - 100 V	-	-	- 1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V _{DS} = - 100 V, T _J = 125 °C	-	-	- 50	
		$V_{GS} = 0 V$	V _{DS} = - 100 V, T _J = 175 °C	-	-	- 250	
On-State Drain Current ^a	I _{D(on)}	V _{GS} = - 10 V	$V_{DS} \le -5 V$	- 30	-	-	Α
		V _{GS} = - 10 V	I _D = - 9.2 A	-	0.033	-	Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 10 V	I _D = - 9.2 A, T _J = 125 °C	-	0.074	-	
Drain-Source On-State Resistance	i DS(on)	$V_{GS} = -10 \text{ V}$	I _D = - 9.2 A, T _J = 175 °C	-	0.093	-	
		$V_{GS} = -4.5 \text{ V}$	I _D = - 7.7 A	-	0.037	-	
Forward Transconductance ^b	9 _{fs}	V _{DS} =	V _{DS} = - 15 V, I _D = - 9.2 A		35	-	S
Dynamic ^b							
Input Capacitance	C _{iss}			-	4433	5545	
Output Capacitance	C _{oss}	$V_{GS} = 0 V$ $V_{DS} = -25 V, f = 1 MHz$	-	301	380	рF	
Reverse Transfer Capacitance	C _{rss}]		-	208	260	1
Total Gate Charge ^c	Qg			-	96	144	
Gate-Source Charge ^c	Q _{gs}	V _{GS} = - 10 V	V _{DS} = - 50V, I _D = - 9.2 A	-	8.4	-	nC
Gate-Drain Charge ^c	Q _{gd}	1		-	23.5	-]
Gate Resistance	R_{g}		f = 1 MHz		3.13	4.7	Ω
Turn-On Delay Timec	t _{d(on)}			-	11	17	
Rise Time ^c	t _r	$V_{DD} = \text{-} 50 \text{ V}, \text{R}_{\text{L}} = 6.49 \Omega$ $I_{D} \cong \text{-} 7.7 \text{A}, \text{V}_{\text{GEN}} = \text{-} 10 \text{V}, \text{R}_{\text{g}} = 1.0 \Omega$		-	11	17	ns
Turn-Off Delay Time ^c	t _{d(off)}			-	78	117	
Fall Time ^c	t _f			-	15	23	
Source-Drain Diode Ratings and Characteristics ^b							
Pulsed Current ^a	I _{SM}			-	_	- 150	Α
Forward Voltage	V _{SD}	I _E = - 7.7 A, V _{GS} = 0 V			- 0.8	- 1.5	V

Notes

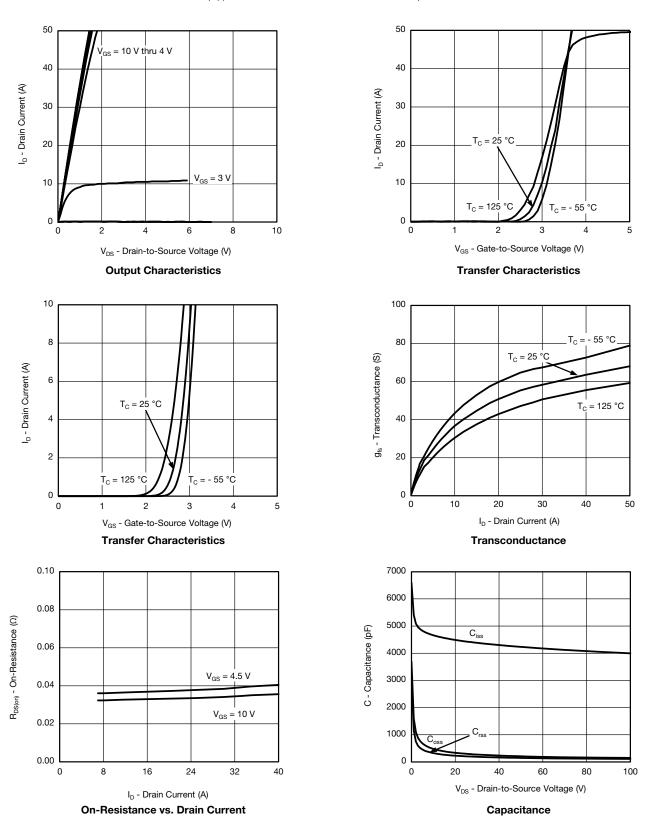
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- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

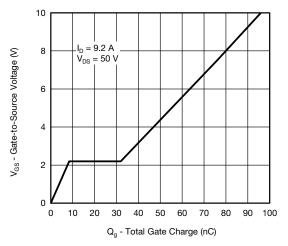


TYPICAL CHARACTERISTICS ($T_A = 25$ °C, unless otherwise noted)

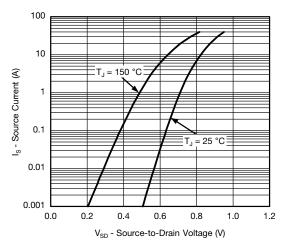




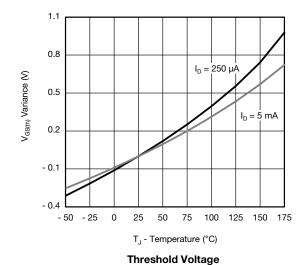
TYPICAL CHARACTERISTICS ($T_A = 25 \, ^{\circ}\text{C}$, unless otherwise noted)

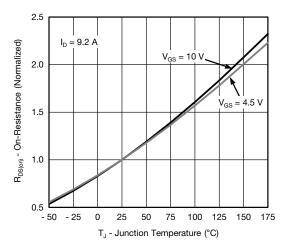


Gate Charge

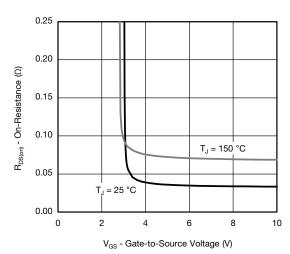


Source Drain Diode Forward Voltage

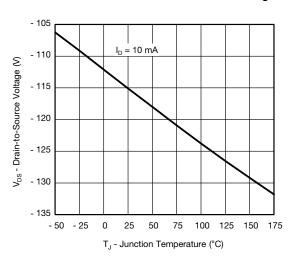




On-Resistance vs. Junction Temperature



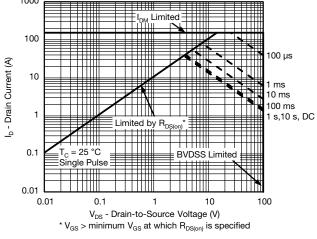
On-Resistance vs. Gate-to-Source Voltage



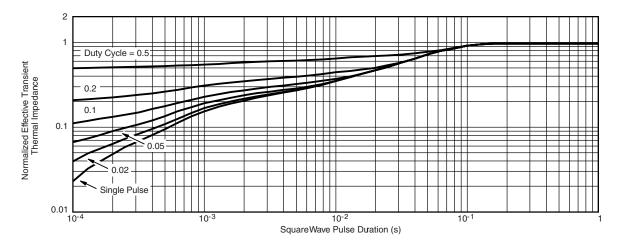
Drain Source Breakdown vs. Junction Temperature



THERMAL RATINGS ($T_A = 25$ °C, unless otherwise noted)



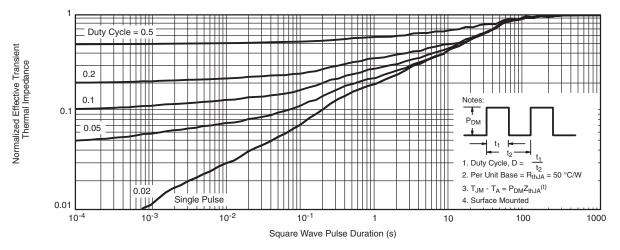
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Case



THERMAL RATINGS (T_A = 25 °C, unless otherwise noted)



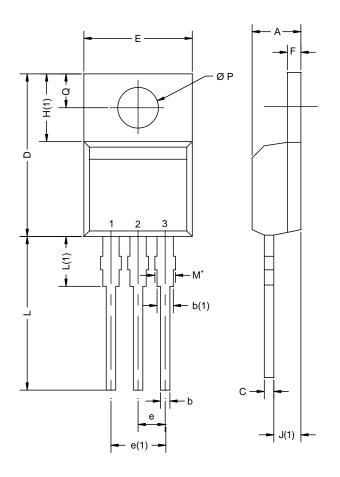
Normalized Thermal Transient Impedance, Junction-to-Ambient

Note

- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction to Ambient (25 °C)
 - Normalized Transient Thermal Impedance Junction to Case (25 °C) are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



TO-220AB



	MILLIM	IETERS	S INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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